

L Number	Hits	Search Text	DB	Time stamp
-	31	irani and mosaic near8 images	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/02/14 15:57
-	13	generat\$3 with (left or right) with (panoramic or mosaic) with image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/02/14 17:33
-	2	generat\$3 with pair with (right or left) with panoramic with image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/02/14 17:49
-	17	(generat\$3 or produc\$3) with (right or left) with panoramic with images	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/02/14 18:03
-	103	(right or left) with panoramic with images	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/02/14 18:05
-	3421	stereo\$5 with pair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 17:35
-	13213	image with strip	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 17:36
-	144	(stereo\$5 with pair) and (image with strip)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 18:06
-	92	((stereo\$5 with pair) and (image with strip)) and generat\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 18:19
-	4	((stereo\$5 with pair) and (image with strip)) and generat\$3) and (project\$3 same (stereoscop\$2 or "3-D" or "3D") same panoramic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 18:24
-	6	((stereo\$5 with pair) and (image with strip)) and (project\$3 same (stereoscop\$2 or "3-D" or "3D") same panoramic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 18:24

-	63	project\$3 same (stereoscop\$2 or "3-D" or "3D") same panoramic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 18:31
-	21	(project\$3 same (stereoscop\$2 or "3-D" or "3D") same panoramic) and projector	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/29 18:31

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